



# STD65N6F3

N-channel 60V - 8.0mΩ - 65A - DPAK  
STripFET™ Power MOSFET

PRELIMINARY DATA

## Features

Type	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>	P <sub>w</sub>
STD65N6F3	60V	< 10.5mΩ	65A	110W

- Standard threshold drive
- 100% avalanche tested

## Description

This n-channel enhancement mode Power MOSFET is the latest refinement of STMicroelectronics' unique "Single Feature Size™" strip-based process, which has decreased the critical alignment steps, offering remarkable manufacturing reproducibility. The outcome is a transistor with extremely high packing density for low on resistance, rugged avalanche characteristics and low gate charge.

## Application

- Switching applications
  - Automotive

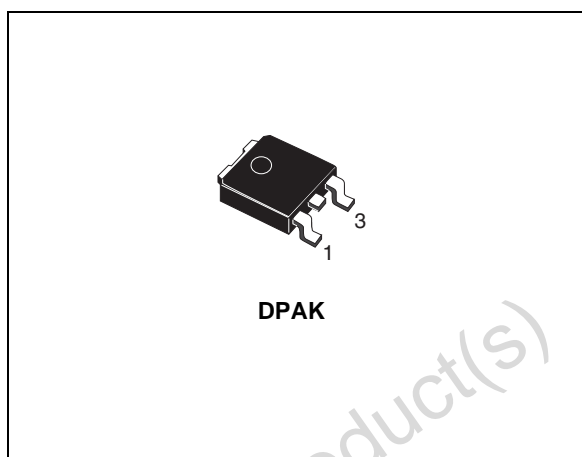


Figure 1. Internal schematic diagram

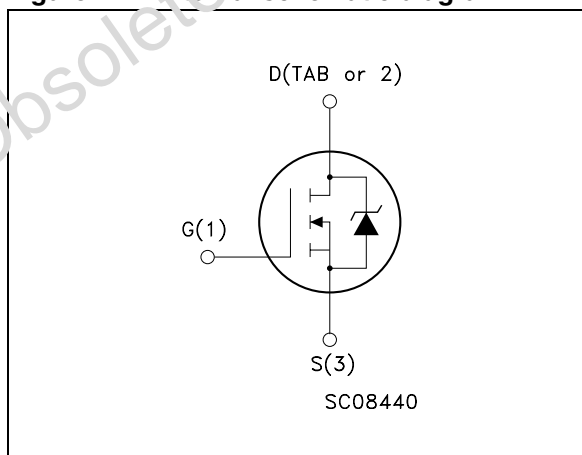


Table 1. Device summary

Order code	Marking	Package	Packaging
STD65N6F3	D65N6F3	DPAK	Tape & reel

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# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage ( $V_{GS}=0$ )	60	V
$V_{GS}$	Gate-Source voltage	$\pm 20$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	65	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	46	A
$I_{DM}^{(1)}$	Drain current (pulsed)	260	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	110	W
	Derating factor	0.73	W/ $^\circ\text{C}$
$dv/dt^{(2)}$	Peak diode recovery voltage slope	Tbd	V/ns
$E_{AS}^{(3)}$	Single pulse avalanche energy	Tbd	mJ
$T_j$ $T_{stg}$	Operating junction temperature Storage temperature	-55 to 175	$^\circ\text{C}$

1. Pulse width limited by safe operating area
2.  $I_{SD} \leq 65\text{A}$ ,  $di/dt \leq 300\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_j \leq T_{jmax}$
3. Starting  $T_j = 25^\circ\text{C}$ ,  $I_d = 32\text{A}$ ,  $V_{dd} = 40\text{V}$

**Table 3. Thermal resistance**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	1.36	$^\circ\text{C}/\text{W}$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb max	50	$^\circ\text{C}/\text{W}$
$T_L$	Maximum lead temperature for soldering purpose	275	$^\circ\text{C}$

1. When mounted on FR-4 board of 1inch<sup>2</sup>, 2oz Cu.

## 2 Electrical characteristics

( $T_{CASE}=25^{\circ}C$  unless otherwise specified)

**Table 4. Static**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown Voltage	$I_D = 250\mu A, V_{GS} = 0$	60			V
$I_{DSS}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = \text{Max rating},$ $V_{DS} = \text{Max rating}, T_c = 125^{\circ}C$			10 100	$\mu A$ $\mu A$
$I_{GSS}$	Gate body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 20V$			$\pm 200$	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2		4	V
$R_{DS(on)}$	Static drain-source on resistance	$V_{GS} = 10V, I_D = 32A$		8.0	10.5	m $\Omega$

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min	Typ.	Max.	Unit
$g_{fs}^{(1)}$	Forward transconductance	$V_{DS} = 25V, I_D = 32A$		Tbd		S
$C_{iss}$	Input capacitance	$V_{DS} = 25V, f = 1MHz, V_{GS} = 0$		2200		pF
$C_{oss}$	Output capacitance			500		pF
$C_{rss}$	Reverse transfer capacitance			25		pF
$Q_g$	Total gate charge	$V_{DD} = 48V, I_D = 65A$		35	Tbd	nC
$Q_{gs}$	Gate-source charge	$V_{GS} = 10V$		15		nC
$Q_{gd}$	Gate-drain charge	(see Figure 5)		10		nC

1. Pulsed: pulse duration = 300 $\mu s$ , duty cycle 1.5%

**Table 6. Switching on/off (inductive load)**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ $t_r$	Turn-on delay time Rise time	$V_{DD}=30V, I_D= 32A,$ $R_G=4.7\Omega, V_{GS}=10V$ <i>(see Figure 4),</i> <i>(see Figure 7)</i>		Tbd Tbd		ns ns
$t_{d(off)}$ $t_f$	Turn-off delay time Fall time	$V_{DD}=30V, I_D= 32A,$ $R_G=4.7\Omega, V_{GS}=10V$ <i>(see Figure 4),</i> <i>(see Figure 7)</i>		Tbd Tbd		ns ns

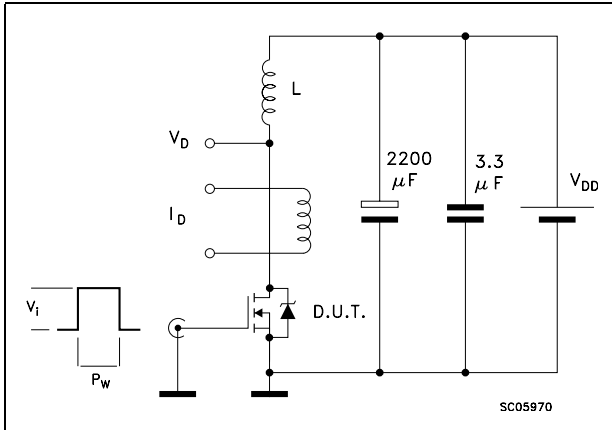
**Table 7. Source drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current				65	A
$I_{SDM}$	Source-drain current (pulsed) <sup>(1)</sup>				260	A
$V_{SD}$	Forward on voltage	$I_{SD}=65A, V_{GS}=0$			1.5	V
$t_{rr}$	Reverse recovery time	$I_{SD}=65A, di/dt =100A/\mu s,$ $V_{DD}=30V, T_j=150^\circ C$		50		ns
$Q_{rr}$	Reverse recovery charge	<i>(see Figure 6)</i>		90		nC
$I_{RRM}$	Reverse recovery current			4.0		A

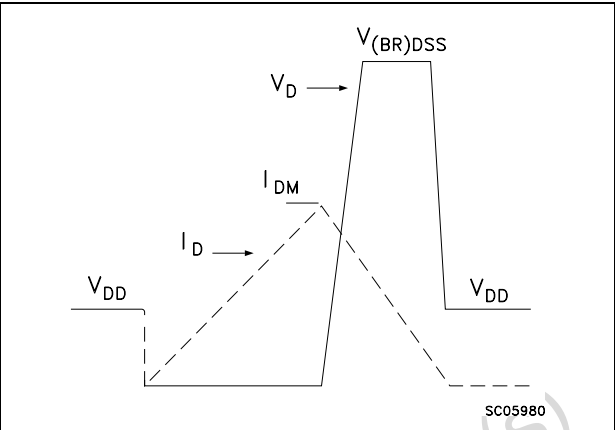
1. Pulsed: pulse duration = 300μs, duty cycle 1.5%

### 3 Test circuit

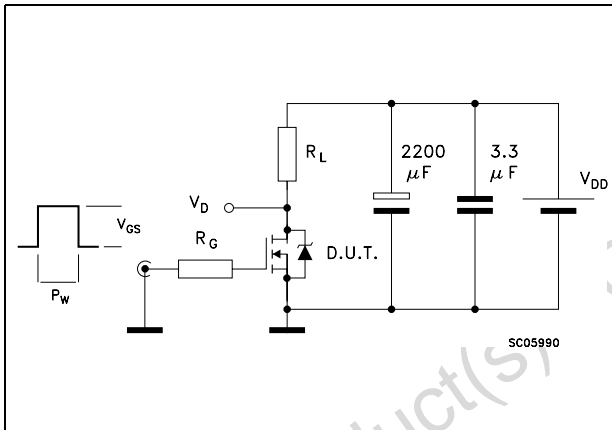
**Figure 2. Unclamped inductive load test circuit**



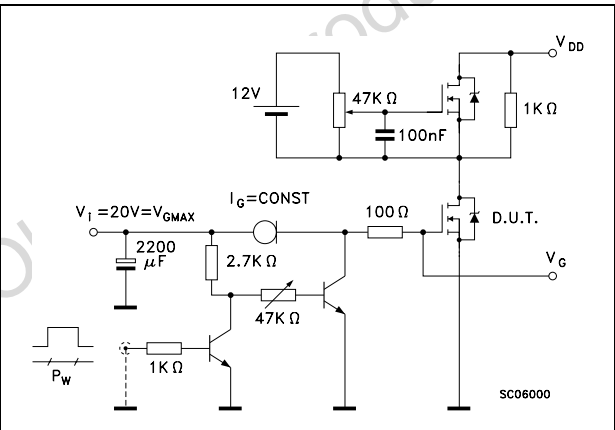
**Figure 3. Unclamped inductive waveform**



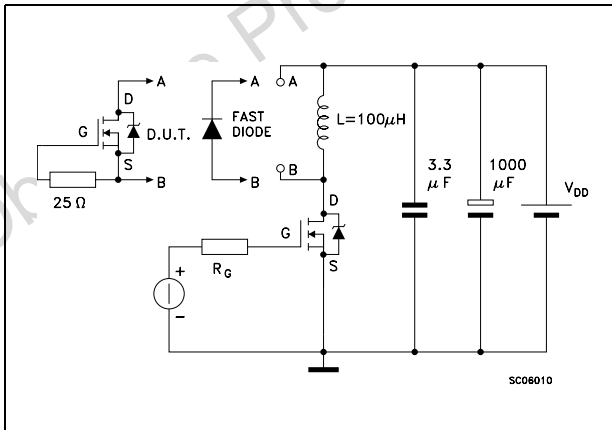
**Figure 4. Switching times test circuit for resistive load**



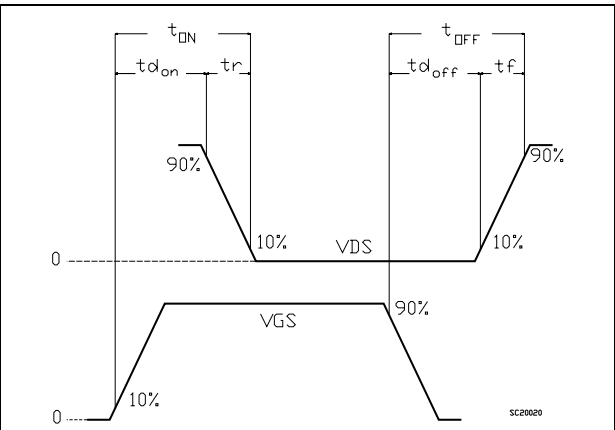
**Figure 5. Gate charge test circuit**



**Figure 6. Test circuit for inductive load switching and diode recovery times**



**Figure 7. Switching time waveform**



## 4 Package mechanical data

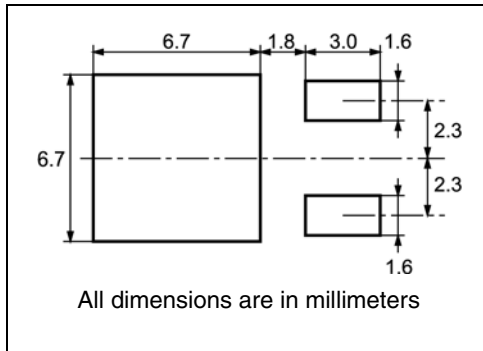
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: [www.st.com](http://www.st.com)

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## 5 Packaging mechanical data

### DPAK FOOTPRINT



### TAPE AND REEL SHIPMENT

DIM.	mm		inch	
	MIN.	MAX.	MIN.	MAX.
A		330		12.992
B	1.5		0.059	
C	12.8	13.2	0.504	0.520
D	20.2		0.795	
G	16.4	18.4	0.645	0.724
N	50		1.968	
T		22.4		0.881

DIM.	mm		inch	
	MIN.	MAX.	MIN.	MAX.
A0	6.8	7	0.267	0.275
B0	10.4	10.6	0.409	0.417
B1		12.1		0.476
D	1.5	1.6	0.059	0.063
D1	1.5		0.059	
E	1.65	1.85	0.065	0.073
F	7.4	7.6	0.291	0.299
K0	2.55	2.75	0.100	0.108
P0	3.9	4.1	0.153	0.161
P1	7.9	8.1	0.311	0.319
P2	1.9	2.1	0.075	0.082
R	40		1.574	
W	15.7	16.3	0.618	0.641

## 6 Revision history

**Table 8. Revision history**

Date	Revision	Changes
10-Jul-2007	1	First release

Obsolete Product(s) - Obsolete Product(s)

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